

SiC JFET Division

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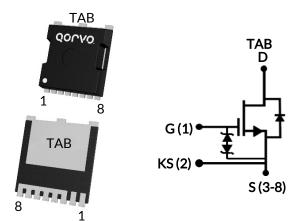






DATASHEET

UJ4SC075008L8S



Part Number	Package	Marking
UJ4SC075008L8S	MO-229	UJ4SC075008







Silicon Carbide (SiC) Cascode JFET -EliteSiC, Power N-Channel, TOLL, 750V, 8.6 mohm

Rev. B, January 2025

Description

The UJ4SC075008L8S is a 750V, $8.6m\Omega$ G4 SiC FET. It is based on a unique 'cascode' circuit configuration, in which a normally-on SiC JFET is co-packaged with a Si MOSFET to produce a normally-off SiC FET device. The device's standard gate-drive characteristics allows use of off-the-shelf gate drivers hence requiring minimal re-design when replacing Si IGBTs, Si superjunction devices or SiC MOSFETs. Available in the space-saving MO-229 package which enables automated assembly, this device exhibits ultra-low gate charge and exceptional reverse recovery characteristics, making it ideal for switching inductive loads and any application requiring standard gate drive.

Features

- On-resistance R_{DS(on)}: 8.6mΩ (typ)
- Operating temperature: 175°C (max)
- Excellent reverse recovery: Q_{rr} = 338nC
- ◆ Low body diode V_{FSD}: 1.1V
- ◆ Low gate charge: Q_G =75nC
- Threshold voltage V_{G(th)}: 4.5V (typ) allowing 0 to 15V drive
- Low intrinsic capacitance
- ESD protected, HBM class 2
- MO-229 package for faster switching, clean gate waveforms

Typical applications

- Solid state relays and circuit-breakers
- Line rectification and active-bridge rectification circuits in AC/DC front-ends
- EV charging
- PV inverters
- Switch mode power supplies
- Power factor correction modules
- Motor drives
- Induction heating













Maximum Ratings

Parameter	Symbol	Test Conditions	Value	Units
Drain-source voltage	V_{DS}		750	V
Gate-source voltage	V_{GS}	DC	-20 to +20	V
Gate-source voltage	V GS	AC (f > 1Hz)	-25 to +25	٧
Continuous drain current ¹	I _D	T _C < 104°C	106	Α
Pulsed drain current ²	I _{DM}	T _C = 25°C	344	Α
Single pulsed avalanche energy ³	E _{AS}	$L=15mH$, $I_{AS}=5.2A$	202	mJ
SiC FET dv/dt ruggedness	dv/dt	$V_{DS} \le 500V$	100	V/ns
Power dissipation	P _{tot}	T _C = 25°C	600	W
Maximum junction temperature	$T_{J,max}$		175	°C
Operating and storage temperature	T_J, T_{STG}		-55 to 175	°C
Reflow soldering temperature	T_{solder}	reflow MSL 1	260	°C

- 1. Limited by bondwires
- 2. Pulse width t_p limited by $T_{J,max}$
- 3. Starting $T_J = 25^{\circ}C$

Thermal Characteristics

Parameter	Symbol	Test Conditions	Value			Units
Parameter	Syllibol	rest Conditions	Min	Тур	Max	Units
Thermal resistance, junction-to-case	$R_{\theta JC}$			0.19	0.25	°C/W



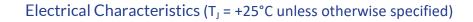












Typical Performance - Static

Parameter	Symbol	vmbol Test Conditions Value			Units		
rai affictei	Syllibol	rest Conditions	Min	Тур	Max	Offics	
Drain-source breakdown voltage	BV _{DS}	$V_{GS}=0V, I_D=1mA$	750			V	
		V _{DS} =750V,		4	84	μΑ	
Total drain leakage current	I _{DSS}	V_{GS} =0V, T_J =25°C		-			
Total di ain leakage cultetit	D33	V_{DS} =750V, V_{GS} =0V, T_J =175°C		35			
Total gate leakage current	I _{GSS}	V _{DS} =0V, T _J =25°C, V _{GS} =-20V / +20V		2	20	μА	
Drain-source on-resistance	R _{DS(on)}	V_{GS} =12V, I_D =70A, T_J =25°C		8.6	11.4		
		V_{GS} =12V, I_{D} =70A, T_{J} =125°C		14.4		mΩ	
		V_{GS} =12V, I_{D} =70A, T_{J} =175°C		19			
Gate threshold voltage	$V_{G(th)}$	V_{DS} =5V, I_{D} =10mA	3.5	4.5	5.5	V	
Gate resistance	R _G	f=1MHz, open drain		2.3		Ω	

Typical Performance - Reverse Diode

Parameter	Symbol	Test Conditions	Value			Units
	Syllibol	rest Conditions	Min	Тур	Max	Ullits
Diode continuous forward current ¹	I _S	T _C < 104°C			106	Α
Diode pulse current ²	$I_{S,pulse}$	T _C =25°C			344	Α
	V _{FSD}	V _{GS} =0V, I _S =35A, T _J =25°C		1.10	1.24	V
Forward voltage		V _{GS} =0V, I _S =35A, T _J =175°C		1.14		
Reverse recovery charge	Q_{rr}	V_{DS} =400V, I_{S} =70A, V_{GS} =0V, R_{G} =33 Ω		338		nC
Reverse recovery time	t _{rr}	di/dt=2500A/μs, T _J =25°C		29		ns
Reverse recovery charge	Q _{rr}	V_{DS} =400V, I_{S} =70A, V_{GS} =0V, R_{G} =33 Ω		375		nC
Reverse recovery time	t _{rr}	di/dt=2500A/μs, T _J =150°C		32		ns













Typical Performance - Dynamic

Posterior	6	Total Constitution		Value		11.20
Parameter	Symbol	Test Conditions -	Min	Тур	Max	Units
Input capacitance	C _{iss}	V _{DS} =400V, V _{GS} =0V		3340		
Output capacitance	C _{oss}	f=100kHz		230		pF
Reverse transfer capacitance	C_{rss}			1.4		
Effective output capacitance, energy related	C _{oss(er)}	V _{DS} =0V to 400V, V _{GS} =0V		286		pF
Effective output capacitance, time related	$C_{oss(tr)}$	V_{DS} =0V to 400V, V_{GS} =0V		605		pF
C _{OSS} stored energy	E _{oss}	V _{DS} =400V, V _{GS} =0V		23		μЈ
Total gate charge	Q_{G}	V _{DS} =400V, I _D =70A,		75		
Gate-drain charge	Q_{GD}	V_{DS} =400V, I_D -70A, V_{GS} = 0V to 15V		13		nC
Gate-source charge	Q_{GS}	V _{GS} - 0 V to 13 V		22		
Turn-on delay time	t _{d(on)}	Notes 4 and 5, V _{DS} =400V, I _D =70A, Gate Driver =0V to +15V,		17		ns
Rise time	t _r			25		
Turn-off delay time	t _{d(off)}			65		
Fall time	t _f	Turn-on $R_{G,EXT} = 1\Omega$,		14		
Turn-on energy including R_S energy	E _{ON}	Turn-off $R_{G,EXT} = 5\Omega$, inductive Load, FWD:		220		μ
Turn-off energy including R _S energy	E _{OFF}	same device with $V_{GS} = 0V$		181		
Total switching energy	E _{TOTAL}	and $R_G = 5\Omega$, RC snubber:		401		
Snubber R _S energy during turn-on	E _{RS_ON}	$R_S=5\Omega$ and $C_S=560$ pF, $T_1=25$ °C		13		
Snubber R _S energy during turn-off	E _{RS_OFF}	1 ₃ -25 C		50		
Turn-on delay time	t _{d(on)}			18		
Rise time	t _r	Notes 4 and 5, V _{DS} =400V, I _D =70A, Gate		28		nc
Turn-off delay time	t _{d(off)}	Driver =0V to +15V,		68		ns
Fall time	t _f	Turn-on $R_{G,EXT} = 1\Omega$,		13		
Turn-on energy including R _S energy	E _{ON}	Turn-off $R_{G,EXT}$ =5 Ω , inductive Load, FWD: same device with V_{GS} = 0V and R_{G} = 5 Ω , RC snubber:		245		
Turn-off energy including R _S energy	E _{OFF}			211		
Total switching energy	E _{TOTAL}			456		μJ
Snubber R _S energy during turn-on	E _{RS_ON}	$R_s=5\Omega$ and $C_s=560$ pF, $T_s=150$ °C		13		
Snubber R _S energy during turn-off	E _{RS_OFF}	., 255 5		50		

^{4.} Measured with the switching test circuit in Figure 26.

^{5.} In this datasheet, all the switching energies (turn-on energy, turn-off energy and total energy) presented in the tables and Figures include the device RC snubber energy losses.





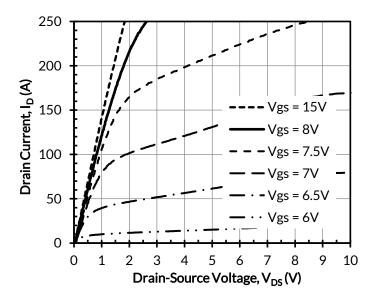


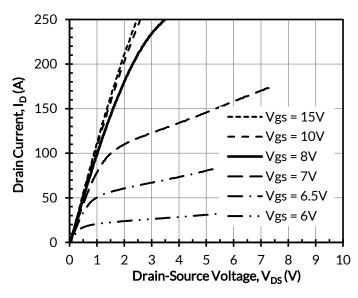






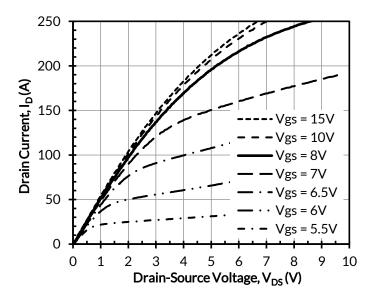
Typical Performance Diagrams





< 250µs

Figure 1. Typical output characteristics at $T_J = -55$ °C, tp Figure 2. Typical output characteristics at $T_J = 25$ °C, tp < 250µs



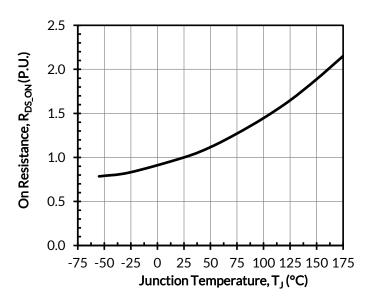


Figure 3. Typical output characteristics at $T_J = 175$ °C, tp Figure 4. Normalized on-resistance vs. temperature at < 250µs

 V_{GS} = 12V and I_D = 70A



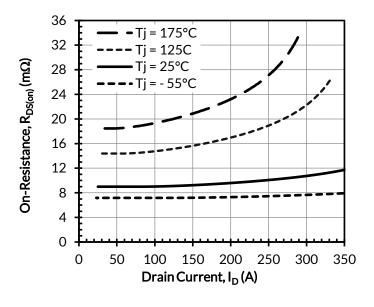












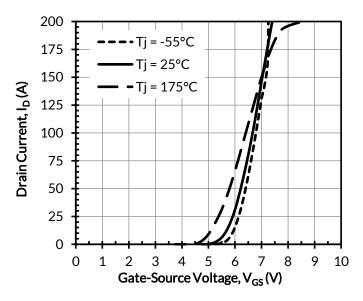
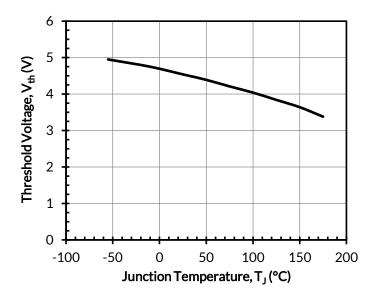
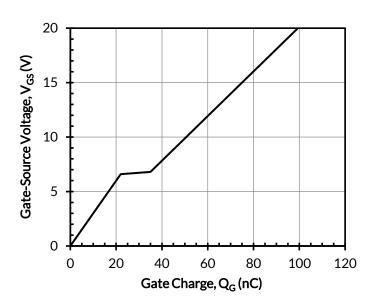


Figure 5. Typical drain-source on-resistances at V_{GS} = 12V

Figure 6. Typical transfer characteristics at $V_{DS} = 5V$





 V_{DS} = 5V and I_D = 10mA

Figure 7. Threshold voltage vs. junction temperature at Figure 8. Typical gate charge at V_{DS} = 400V and I_{D} = 70A













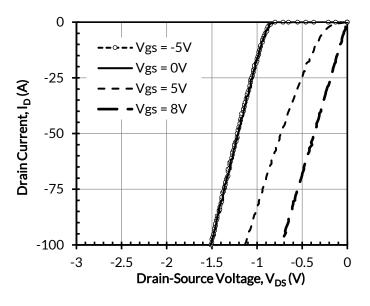
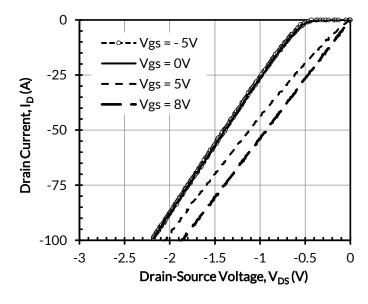


Figure 9. 3rd quadrant characteristics at $T_J = -55$ °C

Figure 10. 3rd quadrant characteristics at $T_J = 25$ °C



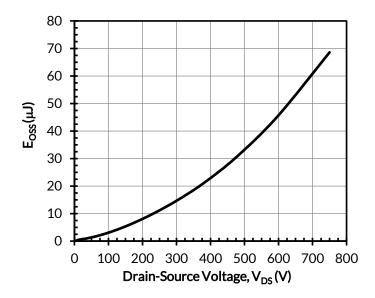


Figure 11. 3rd quadrant characteristics at $T_J = 175$ °C

Figure 12. Typical stored energy in C_{OSS} at $V_{GS} = 0V$



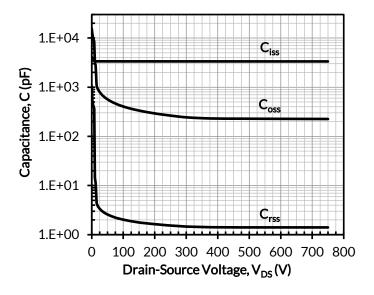












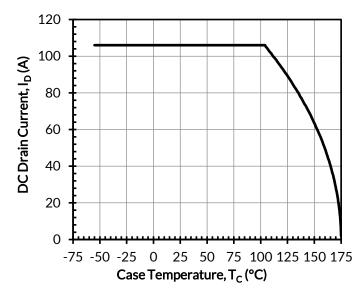
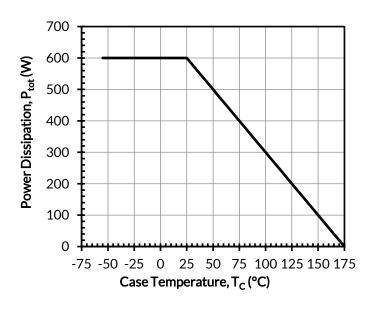


Figure 13. Typical capacitances at f = 100kHz and V_{GS} = 0V

Figure 14. DC drain current derating



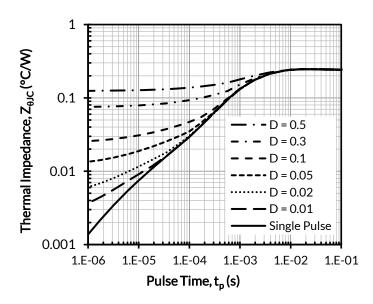


Figure 15. Total power dissipation

Figure 16. Maximum transient thermal impedance



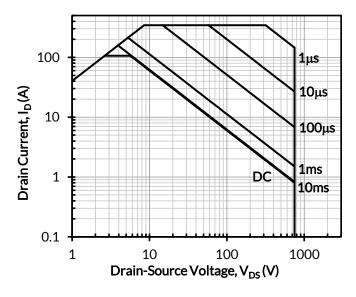








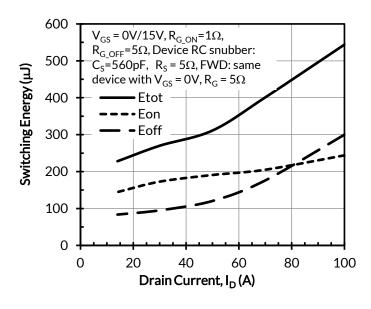




400 350 300 250 200 150 $I_{S} = 70A$, 100 $di/dt = 2500A/\mu s$, 50 $V_{GS} = 0V, R_G = 33\Omega$ 0 0 25 100 125 Junction Temperature, T_J (°C)

Figure 17. Safe operation area at $T_C = 25$ °C, D = 0, Parameter t_p

Figure 18. Reverse recovery charge Qrr vs. junction temperature at $V_{DS} = 400V$



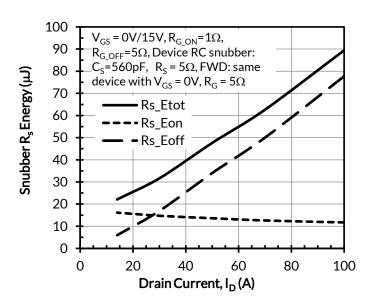


Figure 19. Clamped inductive switching energy vs. drain Figure 20. RC snubber energy loss vs. drain current at current at V_{DS} = 400V and T_J = 25°C

 $V_{DS} = 400V$ and $T_J = 25$ °C



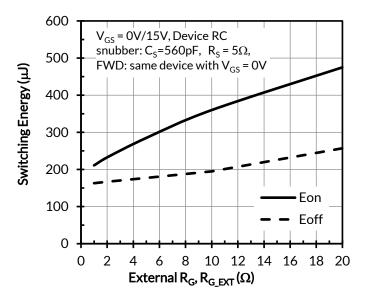












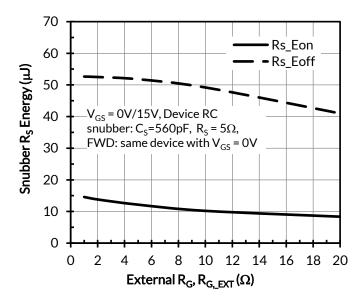
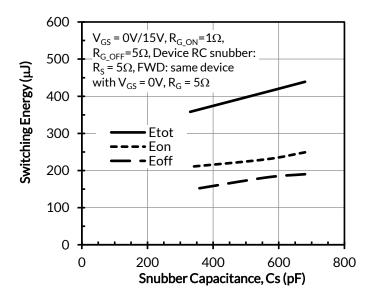


Figure 21. Clamped inductive switching energy vs. $R_{G,EXT}$ Figure 22. RC snubber energy losses vs. $R_{G,EXT}$ at V_{DS} = at V_{DS} = 400V, I_D = 70A, and T_J = 25°C

400V, $I_D = 70A$, and $T_J = 25$ °C



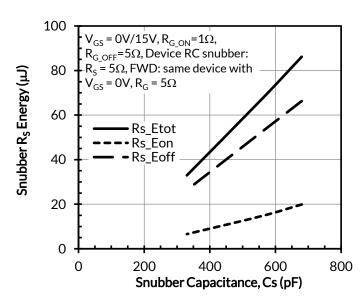


Figure 23. Clamped inductive switching energy vs. Figure 24. RC snubber energy loss vs. Snubber Snubber Capacitance Cs at V_{DS} = 400V, I_D = 70A, and T_J = Capacitance Cs at V_{DS} = 400V, I_D = 70A, and T_J = 25°C 25°C





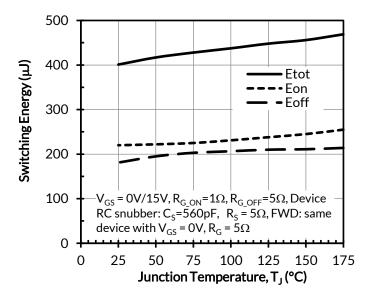












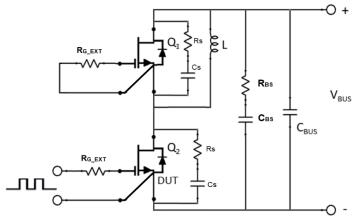


Figure 25. Clamped inductive switching energies vs. junction temperature T_J at V_{DS} = 400V, and I_D = 70A

Figure 26. Schematic of the half-bridge mode switching test circuit. Note, a device snubber (Rs = 5Ω , Cs = 560pF) and bus RC snubber (R_{BS} = 1Ω , C_{BS}=100nF) is used to reduce the power loop high frequency oscillations.















SiC FETs are enhancement-mode power switches formed by a high-voltage SiC depletion-mode JFET and a low-voltage silicon MOSFET connected in series. The silicon MOSFET serves as the control unit while the SiC JFET provides high voltage blocking in the off state. This combination of devices in a single package provides compatibility with standard gate drivers and offers superior performance in terms of low on-resistance ($R_{DS(on)}$), output capacitance (C_{oss}), gate charge (Q_G), and reverse recovery charge (Q_{rr}) leading to low conduction and switching losses. The SiC FETs also provide excellent reverse conduction capability eliminating the need for an external anti-parallel diode. Like other high performance power switches, proper PCB layout design to minimize circuit parasitics is strongly recommended due to the high dv/dt and di/dt rates. An external gate resistor is recommended when the FET is working in the diode mode in order to achieve the optimum reverse recovery performance. For more information on SiC FET operation, see www.unitedsic.com.

A snubber circuit with a small $R_{(G)}$, or gate resistor, provides better EMI suppression with higher efficiency compared to using a high $R_{(G)}$ value. There is no extra gate delay time when using the snubber circuitry, and a small $R_{(G)}$ will better control both the turn-off $V_{(DS)}$ peak spike and ringing duration, while a high $R_{(G)}$ will damp the peak spike but result in a longer delay time. In addition, the total switching loss when using a snubber circuit is less than using high $R_{(G)}$, while greatly reducing $E_{(OFF)}$ from mid-to-full load range with only a small increase in $E_{(ON)}$. Efficiency will therefore improve with higher load current. For more information on how a snubber circuit will improve overall system performance, visit the UnitedSiC website at www.unitedsic.com

Important notice

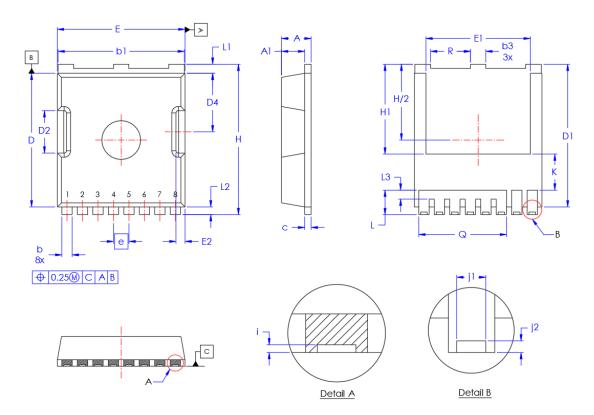
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Datasheet: UJ4SC075008L8S Rev. B, January 2025



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PACKAGE OUTLINE



TO-LL				
SYMBOL	Va			
	Min	Max		
A	2.15	2.45		
Al	1.80	REF		
b	0.65	0.90		
b1	9.65	9.95		
b3	1.10	1.30		
С	0.40	0.60		
D	10.18	10.58		
DI	10.88	11.28		
D2	3.15	3.45		
D4	4.40	4.70		
Е	9.70	10.10		
El	7.95	8.25		
E2	0.60 0.80			
е	1.20 BSC			
Н	11.48	11.88		
HI	6.80	7.10		
i	0.10	REF		
jl	0.46	REF		
j2	0.20	REF		
K	2.80	REF		
L	1.40	2.10		
L1	0.50	0.90		
L2	0.48	0.72		
L3	0.30	0.80		
Q	6.80 REF			
R	3.00	3 20		

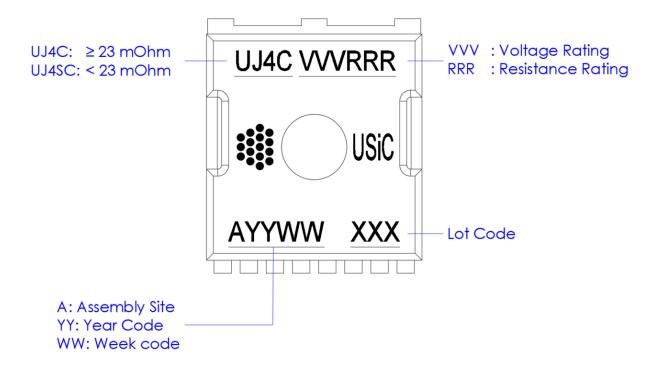
Note:

- 1. All dimensions in millimeters
- 2. Dimensions does not include Burrs and Mold Flashes



TOLL PACKAGE OUTLINE, PART MARKING, TAPE AND REEL SPECIFICATION	Page 2 of 4
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PART MARKING



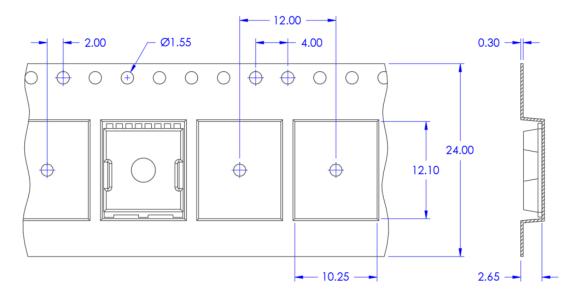
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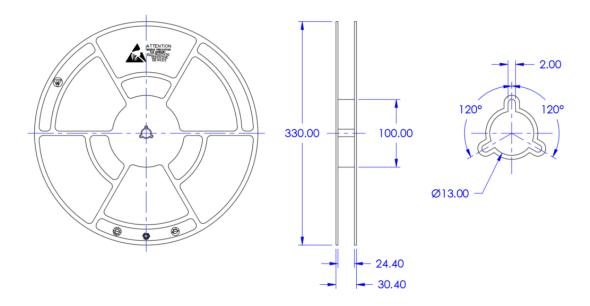
TOLL PACKAGE OUTLINE, PART MARKING, TAPE AND REEL SPECIFICATION	Page 3 of 4
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PACKING TYPE

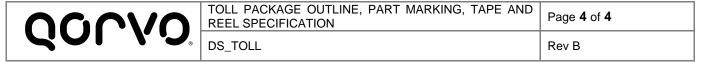
Carrier Tape



Reel



All dimensions in millimeters Quantity per Reel: 2000 units



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REVISION HISTORY

Revision	Create Date (mm/dd/yyyy)	Description of Change	Initiator of Change
Α	10/13/2023	Initial Production Release	Glenn Galang
В	01/31/2024	Corrected device orientation inside carrier tape pocket (Page 3)	Glenn Galang

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